

# G.8262.1/G.8262 EECs Conformance Test

Testing eEECs/EECs as per ITU-T G.8262.1/G.8262 using Paragon-neo

- Noise Generation
- Noise Tolerance
- Noise Transfer
- Transient Response
- Holdover Performance



This Test Guide shows how the Paragon-neo can be used to perform the tests specified in the ITU-T G.8262.1/G.8262 standards for proving SyncE wander and jitter performance at rates up to 100GbE. The tests include noise generation, noise tolerance and transfer, phase transient response and holdover performance. These are compulsory tests for SyncE equipment or systems, with performance criteria for both standard and enhanced EECs.

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# Hardware and Software Required

# Paragon-neo

Opt. NEO-1G-10G 1/10GbE interface support (if the Device-Under-Test (DUT) has 1 and/or 10G interfaces)

Opt. NEO-25G 25GbE interface support (if the DUT has 25G interfaces) Opt. NEO-100G 100GbE interface support (if the DUT has 100G interfaces) Opt. NEO-40G 40GbE interface support (if the DUT has 40G interfaces)

Opt. NEO-SyncE-Wander SyncE Wander and ESMC

Opt. NEO-SyncE-Jitter-XX SyncE Jitter (separate options are available based on required interfaces)

Software version: 09.00.XX and later.

#### Accessories

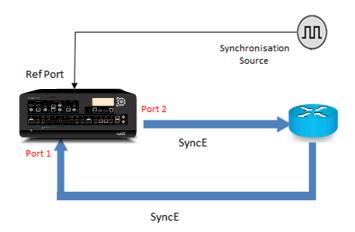
• Optical Transceivers as required – recommended optics lists are available for Jitter testing

• Cables as required

# **Document References**

- Recommendation ITU-T G.8262.1 Timing characteristics of Enhanced EEC (eEEC)
- Recommendation ITU-T G.8262 Timing characteristics of Ethernet Equipment Clock (EEC)
- Recommendation ITU-T G.8261 Timing and synchronization aspects in packet networks

# 2. Connecting an eEEC/EEC to Paragon-neo



# **Paragon-neo Front Panel**

# **Optical Interfaces:**

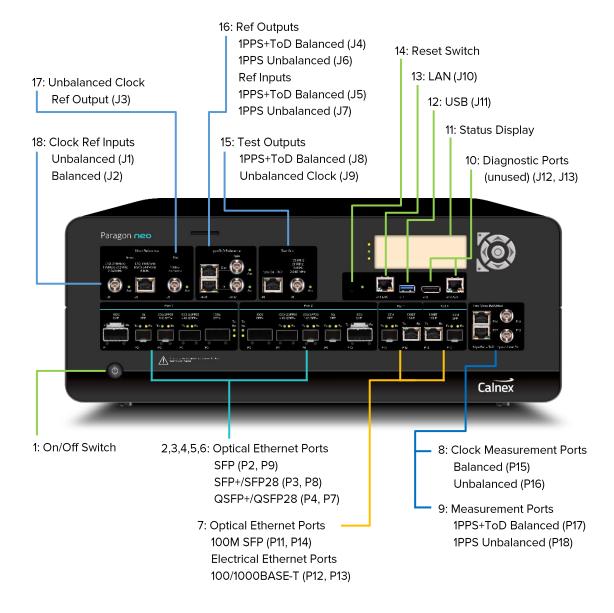
- 100GbE (QSFP28)
- 50GbE (QSFP28)
- 40GbE (QSFP+)
- 25GbE (SFP28)
- 10GbE (SFP+)
- 1GbE (SFP)

# **Reference Clock Inputs:**

• 2.048/10MHz (Recommended)

# **1PPS Measurement Inputs:**

- 1PPS Balanced (RJ48)
- 1PPS Unbalanced (BNC)



# Paragon-neo A (PAM4) Front Panel

# **PAM4 Optical Interfaces:**

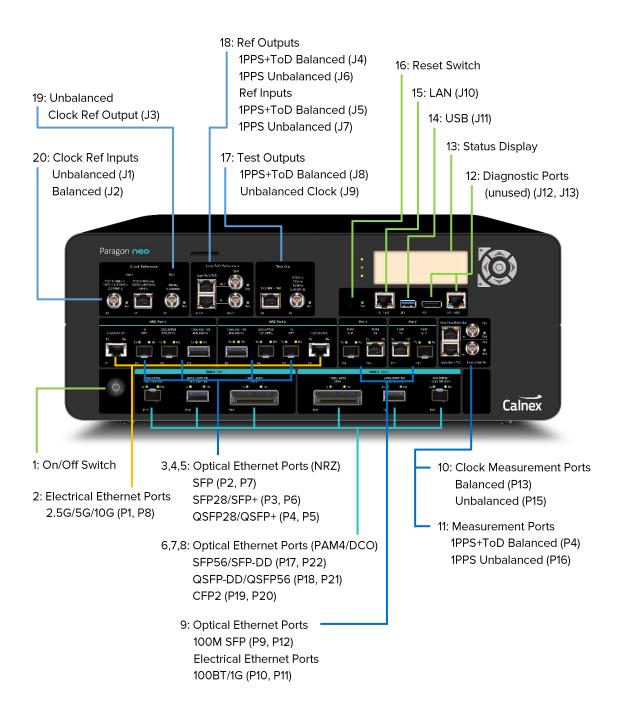
• 400GbE (QSFP-DD) • 50GbE (SFP56)

# **Reference Clock Inputs:**

• 2.048/10MHz (Recommended)

# **1PPS Measurement Inputs:**

- 1PPS Balanced (RJ48)
- 1PPS Unbalanced (BNC)



# How to Configure the Paragon-neo for G.8262.1/G.8262 Wander Tests

The following steps are required to set up the Paragon-neo prior to performing G.8273.2 Conformance tests:

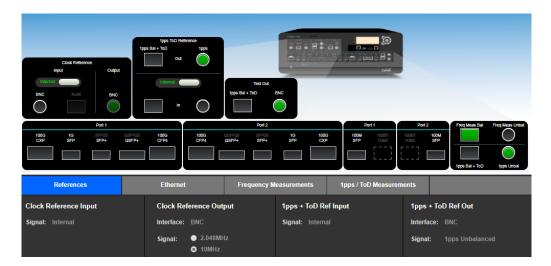
- 3.1. Connection to Paragon-neo
- 3.2. Configuration of Physical Connections
- 3.3. Test Configuration

# 3.1 Connection to Paragon-neo

- 1. Verify the physical connections have been completed as described in Section 2.
- 2. From a PC on the same network, open a browser and enter the IP address of the Paragon-neo unit.
- 3. If directed to the Home Page, select **SyncE Wander** operating mode.
- 4. See the Paragon-neo Getting Started Guide for more details.

# 3.2 Configuration of Physical Connections

1. Select **Setup Ports** then from the onscreen display, select the reference and test ports to be used.



#### 3.3 Test Configuration

1. Select Run Apps.



Note: Once you have selected this, the status of Port 1/Port 2 Link and Port 1/Port 2 Packets should be green. The Reference Lock should be green. The Paragon-neo GUI will display SyncE.

Lock is white. This verifies that the Clock is recovered from Rx > Tx box is unchecked, meaning that the Paragonneo is using its internal or an external clock.

# **ESMC** Generation



The Paragon-neo can generate ESMC messages on both Ports 1 and 2. For SyncE conformance testing, ESMC messages are generated on Port 2 with a user-defined Quality Level (QL) such as PRC.

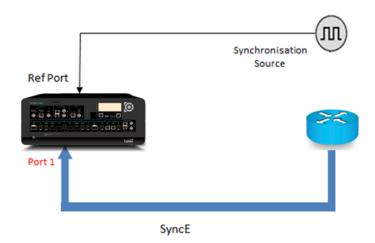
- 2. Select Port 2 tab (which is the output from the Paragon-neo and input to eEEC/EEC).
- 3. By default, Paragon-neo is configured to use Enhanced SSM message formats. Unselecting the tick-box configures Paragon-neo to generate standard SSM message format.
- 4. Selecting the desired Network Option from the drop-down menu pre-populates the appropriate range of SSM codes.

Note: The Network Option should match that of the DUT to ensure that the SSM code is correctly processed by the DUT.

- 5. Set **SSM code** to e.g. QL-PRC, which tells the eEEC/EEC that the clock from the Paragon-neo is of PRC quality.
- 6. Generate ESMC messages by selecting the button. The button LED will turn green to indicate the Paragonneo is generating ESMC packets.

Note: After any setup changes to the Paragon-neo, ensure the device under test has had time to settle before making any measurements.

# 4. Measuring Frequency Accuracy – G.8262.1/G.8262 Section 6



	Input Stimulus	Pass/Fail Criteria	Notes
eEEC	Free run	±4.6ppm	Values of one month and one year have been proposed.
EEC Option 1	Free run	±4.6ppm	Recommend to test for an hour, longer if close to limits.
EEC Option 2	Holdover	±4.6ppm	Recommend to test for an hour, longer if close to limits.

# **Measurement Process**

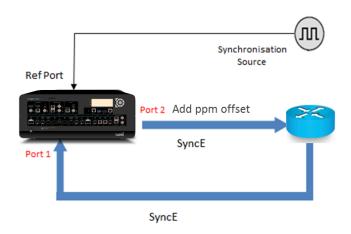
- 1. Connect the eEEC/EEC to Paragon-neo as shown above.
- 2. Set up the Paragon-neo GUI as described in Section 3.
- 3. Select Run Apps.



- button on the connected port (Port 1) to start the measurement.
- 5. To stop the measurement after a pre-defined period for running the test, select the
- 6. Select to pull up the results in a separate browser tab.
- 7. The CAT will provide the ppm frequency accuracy in the **Frequency Offset Removal** section at the right of the graph shown below in the red highlighted box. Compare this value to the requirements for the equipment type under test.



# 5. Pull-in, Hold-in and Pull-out Ranges – G.8262.1/G.8262 Section 7



# Pull-in Range (G.8262.1/G.8262 Section 7.1)

The Pull-in range is defined as the largest offset between a subordinate clock's reference frequency and a specified nominal frequency, within which the subordinate clock will achieve locked mode.

	Input Stimulus	Pass/Fail Criteria	Notes
eEEC, EEC Option 1 and EEC Option 2	Apply a large frequency offset ensuring eEEC/EEC is in holdover. Reduce offset until eEEC/EEC locks.	eEEC/EEC locks before offset reaches ±4.6ppm.	Lock can also be monitored by using ESMC (if supported).

# Hold-in Range (G.8262.1/G.8262 Section 7.2)

Hold-in range is defined as the largest offset between a subordinate clock's reference frequency and a specified nominal frequency, within which the subordinate clock maintains lock as the frequency varies arbitrarily slowly over the frequency range.

	Input Stimulus	Pass/Fail Criteria	Notes
eEEC and EEC Option 1		Not Applicable	
EEC Option 2	EEC is locked to the clock from the Paragon-neo. The frequency is then offset to ±4.6ppm.	EEC should remain locked at an offset of ±4.6ppm.	Lock can also be monitored by using ESMC (if supported).

# Pull-out Range (G.8262.1/G.8262 Section 7.3)

Pull-out range is defined as the offset between a subordinate clock's reference frequency and a specified nominal frequency, within which the subordinate clock stays in the locked mode and outside of which the subordinate clock cannot maintain locked mode, irrespective of the rate of the frequency change.

	Input Stimulus	Pass/Fail Criteria	Notes
eEEC and EEC Option 1	eEEC/EEC is locked to the clock from the Paragon-neo. The frequency is then offset until the eEEC/EEC unlocks.	EEC should remain locked at an offset of ±4.6ppm but lock should extend beyond this.	G.8262.1 and G.8262 state this is for further study.
EEC Option 2	EEC Option 2 Not Applicable		

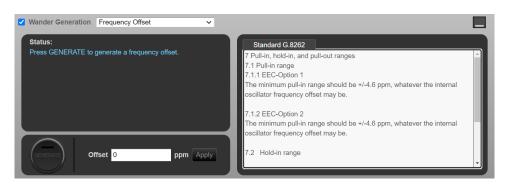
#### **Measurement Process**

- 1. Connect the eEEC/EEC to the Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3, including setting up ESMC with the following settings if using ESMC to monitor if the eEEC/EEC is switching clock references or going into holdover:

Clock Type	Network Option	SSM Code
eEEC	Option 1	QL-PRC
EEC	Option 1	QL-PRC
EEC	Option 2	QL-PRS



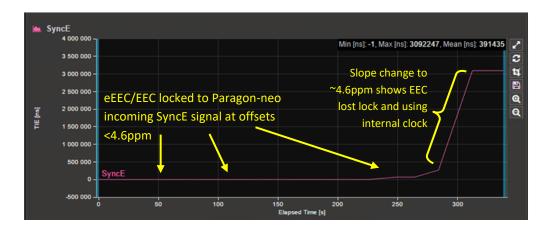
- button on Port 1 to start the measurement.
- 4. Select Wander Generation then select Frequency Offset in the drop-down menu.



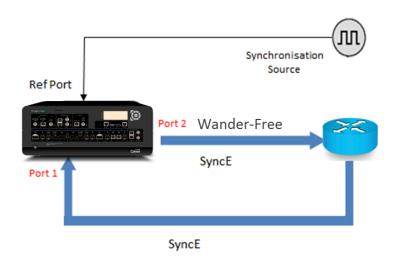
- 5. In the Offset window, add the Frequency Offset required and click the
- 6. To stop the measurement after the desired test duration, select the button.
- 7. Select to pull up the results in a separate browser tab.

8. The Paragon-neo TIE graph indicates if the eEEC/EEC is in or out of lock as shown below.

Note: The capture below shows an example of an EEC tracking lower frequency offsets, then rejecting a high frequency offset to use its internal clock. Actual behaviour may vary between devices.



# 6. Wander (Noise) Generation - G.8262.1/G.8262 Section 8



	Input Stimulus	Pass/Fail Criteria	Notes (G.8262.1/G.8262 masks)
<b>eEEC</b> (Constant Temp)	<ul><li>Locked Mode</li><li>Wander Free reference</li><li>Constant temperature</li></ul>	MTIE and TDEV Pass/Fail masks shown in <b>G.8262.1</b> Section 8.1	G.8262.1: MTIE – Table 1, Figure 1 TDEV – Table 2, Figure 2
EEC Option 1 (Constant Temp)	<ul><li>Locked Mode</li><li>Wander Free reference</li><li>Constant temperature</li></ul>	MTIE and TDEV Pass/Fail masks shown in G.8262 Section 8.1.1	G.8262: MTIE – Table 1, Figure 1 TDEV – Table 3, Figure 2
EEC Option 1 (Temp effects)	Locked Mode     Wander Free reference     Temperature effects	MTIE Pass/Fail masks shown in G.8262 Section 8.1.1	G.8262: MTIE – Table 2, Figure 1 TDEV – G.8262 states for further study
EEC Option 2 (Constant Temp)	<ul><li>Locked Mode</li><li>Wander Free reference</li><li>Constant temperature</li></ul>	MTIE and TDEV Pass/Fail masks shown in G.8262 Section 8.1.2	G.8262: MTIE – Table 4, Figure 3 TDEV – Table 5, Figure 4

G.8262 Section 8.2 also mentions measurements in non-locked mode and refers to Section 11.2 "Long-term phase transient response (Holdover)". That scenario is covered in the corresponding section of this test guide. This scenario for eEEC is for further study.

# **Measurement Setup**

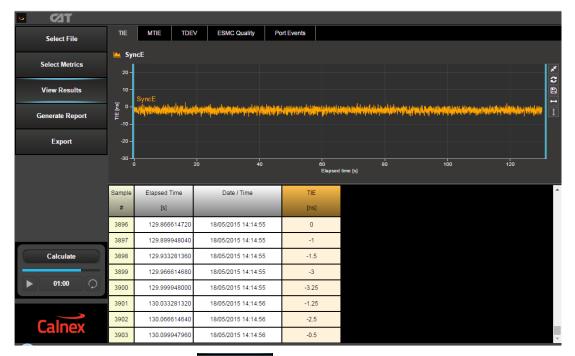
- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3, including setting up ESMC with the following settings if using ESMC to monitor if the eEEC/EEC is switching clock references or going into holdover:

Clock Type	Network Option	SSM Code
eEEC	Option 1	QL-PRC
EEC Option 1	Option 1	QL-PRC
EEC Option 2	Option 2	QL-PRS

#### **Measurement Process**

1. Select the button on Port 1 to start the measurement. To stop the measurement, select the is suggested that the test should run for 3,000 seconds (50minutes).

2. Select to view the results in a separate browser tab. The graph will show the captured TIE.



- Select Metrics 3. To display the MTIE graphs, press then check the MTIE and TDEV tick boxes.
- 4. Select on the left hand side of the graph, select MTIE from the tabs at the top, then select the play button in the Calculate box.



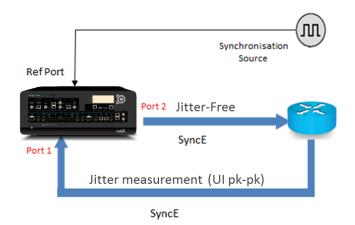
The MTIE results can be reviewed against the G.8262.1/G.8262 masks by selecting a mask from the Metric Mask pull down menu under **Masks** at the right of the graph.

5. To display the TDEV graph, select **TDEV** from the tabs at the top, then select the play button on the Calculate box.



- 6. The TDEV results can be reviewed against the G.8262.1/G.8262 masks by choosing a mask from the Metric Mask pull down menu under **Masks** at the right of the graph.
- 7. Pass/Fail indication against the masks is shown to the right under **Mask Status** with green highlight for a "Pass" red highlight for a "Fail".

#### **7**. Jitter Generation – G.8262.1/G.8262 Section 8.3



	Input Stimulus	Pass/Fail Criteria	Notes
1G	None, unless device requires packet stream to function.	eEEC/EEC Output Jitter ≤0.5 Ulpp in 60-second window, as G.8262.1 8.3.1 Table 3, G.8262 8.3, Table 6.	
<b>10G lanes</b> (100GbE SR10, 40GbE, 10GbE)	None, unless device requires packet stream to function.	EEC Output Jitter ≤0.5Ulpp in 60-second window, as G.8262 8.3, Table 6. eEEC performance is for further study in G.8262.1	For compatibility with EEC, testing eEEC pass/fail as per G.8262 is recommended.
25G lanes (100GbE SR/LR4, 25GbE SR/LR)	None, unless device requires packet stream to function.	EEC Output Jitter ≤1.2Ulpp in 60-second window, as G.8262 8.3, Table 6. eEEC performance is for further study in G.8262.1	For compatibility with EEC, testing eEEC pass/fail as per G.8262 is recommended.

# **Measurement Setup**

- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3.
- 3. On the Paragon-neo Home page, select **SyncE Jitter**.



4. Select the button on the Paragon-neo GUI.

#### **Measurement Process**

1. Select Jitter Measurement.



2. G.8262.1 and G.8262 specify a peak-to-peak (pp) jitter measurement time of 60s. Select **Timing Period**, **60s**.



Select other periods or manual if required, for e.g. experimentation or observing long-term device behaviour. 60s must be selected for making a G.8262.1/G.8262 compliance measurement.

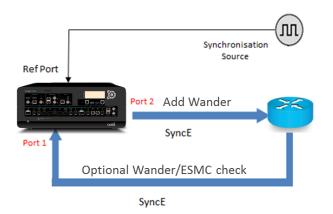
3. If multi-lane interfaces are being tested, select the required Lane Selection. There are four 25G lanes in a 100GbE LR4 interface and ten 10G lanes in a 100GbE SR10 interface. These could exhibit different jitter characteristics, and it is therefore recommended to verify jitter performance on each lane.



button on Port 1 to start the measurement. The results displayed are the peak to peak and RMS 4. Select the jitter values.



# 8. Wander (Noise) Tolerance - G.8262.1/G.8262 Section 9



	Input Stimulus	Pass/Fail Criteria	Notes
eEEC Level 1 <sup>1</sup>	G.8262.1:  • MTIE Wander of G.8261 clause 9.2.1.4 Table 8, Figure 17	<ul> <li>The eEEC must:</li> <li>Maintain the clock within performance limits.</li> <li>Not cause any alarms.</li> <li>Not cause the clock to switch reference.</li> <li>Not cause the clock to go into holdover.</li> </ul>	To check whether the eEEC is switching references or going into holdover, the Paragon-neo can measure the wander and/or ESMC QL of the eEEC output.
eEEC Level 2 <sup>2</sup>	<ul> <li>G.8262.1:</li> <li>MTIE Wander Table 4, Figure 3</li> <li>TDEV Wander Table 5, Figure 4</li> <li>Sinusoidal Wander Table 6, Figure 5</li> </ul>	The eEEC must:  Maintain the clock within performance limits.  Not cause any alarms.  Not cause the clock to switch reference.  Not cause the clock to go into holdover.	To check whether the eEEC is switching references or going into holdover, the Paragon-neo can measure the wander and/or ESMC QL of the eEEC output.
EEC Option 1	<ul> <li>G.8262:</li> <li>MTIE Wander</li></ul>	<ul> <li>The EEC must:</li> <li>Maintain the clock within performance limits.</li> <li>Not cause any alarms.</li> <li>Not cause the clock to switch reference.</li> <li>Not cause the clock to go into holdover.</li> </ul>	To check whether the EEC is switching references or going into holdover, the Paragon-neo can measure the wander and/or ESMC QL of the EEC output.
EEC Option 2	G.8262: • TDEV Wander Table 10, Figure 8	<ul> <li>The EEC must:</li> <li>Maintain the clock within performance limits.</li> <li>Not cause any alarms.</li> <li>Not cause the clock to switch reference.</li> <li>Not cause the clock to go into holdover.</li> </ul>	To check whether the EEC is switching references or going into holdover, the Paragon-neo can measure the wander and/or ESMC QL of the EEC output.

<sup>&</sup>lt;sup>1</sup> A TDEV wander limit is specified in G.8261 clause 9.2.1.4, however the practical method to test (by counting transients) is for further study.

<sup>&</sup>lt;sup>2</sup> A Level 2 eEEC as per G.8262.1 is intended to be capable of operating in a mixed network with EECs, and as such the input stimuli are the same as for an EEC Option 1 as per G.8262.

#### **Measurement Setup**

- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3, including setting up ESMC with the following settings if using ESMC to monitor if the eEEC/EEC is switching clock references or going into holdover:

Clock Type	Network Option	SSM Code
eEEC	Option 1	QL-PRC
EEC Option 1	Option 1	QL-PRC
EEC Option 2	Option 2	QL-PRS

#### **Measurement Process**

- 1. Select the button on the Paragon-neo GUI.
- 2. Select one of the Tolerance options in the **Wander Generation** pull down menu.



There are three methods of generating wander into the eEEC/EEC:

- "Tolerance G.8262 Option 1 MTIE", "Tolerance G.8262 Option 1 TDEV" or "Tolerance G.8262 Option 2 **TDEV"** Wander – fastest and most effective way to evaluate eEEC/EEC
- "Tolerance Table Sine" can be used for finding Maximum Tolerable Wander
- "Tolerance Single Sine" can be used for troubleshooting

# 3. MTIE/TDEV Wander

Paragon-neo can generate MTIE and TDEV Wander as defined in G.8262.1/G.8262. If your instrument does not feature MTIE/TDEV Wander Generation then you can use the Table Sine function, detailed in the next section.

- a) Select the wander mask required from the drop-down list. The mask and the maximum running time will be shown on the right-hand side of the window. Note that for testing eEEC Level 2, the same conditions as EEC Option 1 should be used.
  - Tolerance G.8262.1 Level 1 MTIE Running Time is 1000s (16mins 40secs)
  - Tolerance G.8262 Option 1 MTIE Running Time is 1000s (16mins 40secs)
  - Tolerance G.8262 Option 1 TDEV Running Time is 12000s (3hours 20mins)
  - Tolerance G.8262 Option 2 TDEV Running Time is 12000s (3hours 20mins)

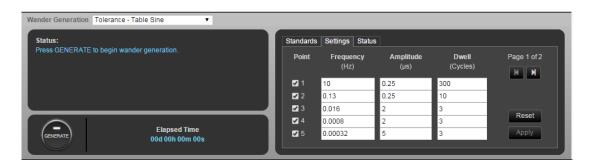
- to start the test. The remaining time will be displayed beside the b) Under Wander Generation, click Generate/Stop button.
- The test will stop automatically after the running time has elapsed. The test can also be stopped by selecting



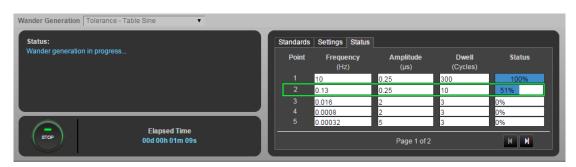
#### 4. Tolerance - Table Sine

Can be used to test Maximum Tolerable Wander. The frequencies used must be chosen carefully to avoid Nyquist effects due to sampling. Calnex have selected appropriate frequencies and corresponding amplitudes for use in the testing of eEEC and EEC clocks, these can be found on the Calnex GdotWhat? knowledgebase at the following link:

https://calnexsolutions.atlassian.net/wiki/spaces/GDW/pages/10322571/What+Frequencies+should+be+used+for+testi ng+SyncE+Wander+Tolerance



Up to 20 different wander parameter sets can be entered in the table. The Paragon-neo will then automatically generate each of the specified wander sets in turn, showing progress in the Status column.



Switching between different sets is always done at a zero crossing to prevent phase steps. To change the Table values, under Settings:

- a) Enter the frequency, amplitude, and dwell time (number of cycles the frequency/amplitude pair will be run) for each wander test point.
  - The same frequency with different amplitudes can be entered to find maximum tolerable wander.
  - The **Reset** button, when checked, will restore the values to those defined in table 9 in G.8262.
  - Only rows that have the Point check box "ticked" will be executed in the test. To skip over a selection, untick the **Point** check box for that selection.
- b) Under Wander Generation click to start the test.
- c) The test can be stopped manually by selecting The test will terminate at the next zero crossing.

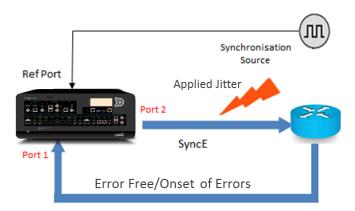
# 5. Single Sinusoidal Wander

Can be used for troubleshooting issues at a specific frequency.



- a) Enter the frequency and amplitude of the desired wander.
- b) Click to start the test.
- to stop the test. The test will terminate at the next zero crossing of the wander frequency, and a c) Click pop up box stating how long to the next zero crossing is displayed.

# 9. Jitter Tolerance - G.8262.1 Section 9.3, G.8262 Section 9.2



SyncE

	Input Stimulus	Pass/Fail Criteria	Notes
1G	<ul> <li>Test packet stream from Paragon-neo or thru-mode traffic (if desired)</li> <li>ESMC stream from Paragon-neo (if desired)</li> <li>Superimpose jitter to G.8262.1 9.3.1 Figure 6/ G.8262 9.2 Figure 9 (same values)</li> </ul>	For all Jitter values presented:  The eEEC/EEC does not drop packets or change ESMC status (dependent on test method used)  The eEEC/EEC does not Error/Alarm during the test  The eEEC/EEC does not go into Holdover	<ul> <li>Allow settling time at each measurement point.</li> <li>Either as pass/fail with presented jitter values at the mask, or a margin test with jitter values above mask.</li> </ul>
<b>10G lanes</b> (100GbE SR10, 40GbE, 10GbE)	<ul> <li>Test packet stream from Paragon-neo or thru-mode traffic (if desired)</li> <li>ESMC stream from Paragon-neo (if desired)</li> <li>Superimpose jitter to G.8262 9.2 Figure 10</li> </ul>	For all Jitter values presented:  The eEEC/EEC does not drop packets or change ESMC status (dependent on test method used)  The eEEC/EEC does not Error/Alarm during the test  The eEEC/EEC does not go into Holdover	<ul> <li>Input Stimulus for eEEC is for further study in G.8262.1 – for compatibility with EEC, using values as per G.8262 9.2 Figure 10 is recommended</li> <li>Allow settling time at each measurement point.</li> <li>Either as pass/fail with presented jitter values at the mask, or a margin test with jitter values above mask.</li> </ul>
<b>25G lanes</b> (100GbE SR/LR4, 25GbE SR/LR)	<ul> <li>Test packet stream from Paragon-neo or thru-mode traffic (if desired)</li> <li>ESMC stream from Paragon-neo (if desired)</li> <li>Superimpose jitter to G.8262 9.2 Table 13</li> </ul>	For all Jitter values presented:  The eEEC/EEC does not drop packets or change ESMC status (dependent on test method used)  The eEEC/EEC does not Error/Alarm during the test  The eEEC/EEC does not go into Holdover	<ul> <li>Input Stimulus for eEEC is for further study in G.8262.1 – for compatibility with EEC, using values as per G.8262 9.2         Table 13 is recommended     </li> <li>Allow settling time at each measurement point.</li> <li>Either as pass/fail with presented jitter values at the mask, or a margin test with jitter values above mask.</li> </ul>

# **Measurement Setup**

- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. On the Paragon-neo Home page, select SyncE Jitter.

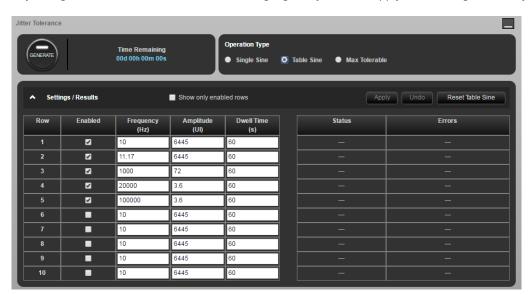


3. Select the button on the Paragon-neo GUI, and then on the Jitter Tolerance panel, select Table Sine.



4. In the Jitter Tolerance Table, enter the Frequency, Amplitude and Dwell Time for each row. The GUI initially shows the standards-compliant default settings for the selected interface. These defaults may be restored by selecting the Reset table sine button.

Any changes made to the table entries will be highlighted yellow. To apply these changes, click Apply.



5. It is possible to measure the received ESMC messages from a device, monitoring for state changes to determine pass/fail directly from the Paragon-neo. Users can switch between the Test Packets and ESMC Measurement method from the **Test Method** drop-down selector in the **Jitter Tolerance** app.



6. Note that it is also possible to select None to switch off other test methods and instead monitor the DUT directly for alarms, etc.

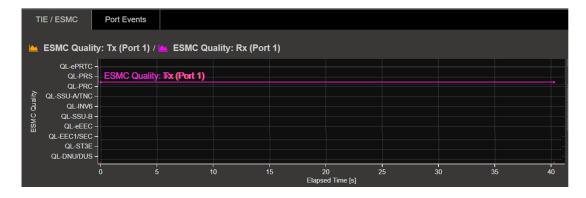
- 7. If ESMC Measurement is selected, then once Generate has been pressed to start the Tolerance test, ESMC measurement will automatically run on Port 1 (which will be the connection back to Paragon-neo from the DUT during Jitter testing), and status can be viewed real-time by selecting CAT. It is then possible to view any state changes, indicating for example that input jitter has not been tolerated and the DUT has switched to an alternate reference source.
- 8. If desired, select Test Packet Settings and configure the test packets generated by the Paragon-neo to meet your requirements. There are selections for Packet Size, Utilization and Payload plus Source and Destination MAC, and IP addresses.



9. To start a Jitter Tolerance measurement, select Generate. The Paragon-neo will now generate Jitter at the selected Jitter Frequency and Amplitude. The test will cycle through all configured settings and stop automatically.

To manually stop the Jitter Tolerance measurement, select the **Stop** button.

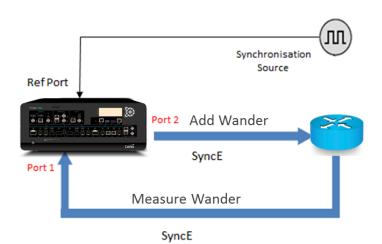
10. If using the ESMC method (recommended), launch CAT to monitor for ESMC state changes indicating that the DUT has lost lock. It is important to verify that the eEEC/EEC does not Error/Alarm or go into Holdover during the test for all jitter values presented.



11. If using the test packets method, the result will indicate if any dropped or out of sequence packets were detected, with a Pass or Fail result appearing for each enabled Frequency/Amplitude pairing after that pair has been tested.



# 10. Wander (Noise) Transfer – G.8262.1/G.8262 Section 10



_	Input Stimulus	Pass/Fail Criteria	Notes
eEEC	Not defined.	In the passband (1Hz-3Hz), the phase gain of the eEEC should be smaller than 0.2dB (2.3%).	There is no definition of the input stimulus to be used in G.8262.1. it is suggested that the frequency values are carefully chosen to avoid aliasing effects, and provide coverage below, in and above the passband, with testing including assessment of filter roll-off characteristics — Calnex provide recommended input values and test masks directly in Paragonneo GUI
EEC Option 1	Not defined.	In the passband (1Hz-10Hz), phase gain of the EEC should be smaller than 0.2dB (2.3%).	There is no definition of the input stimulus to be used in G.8262. it is suggested that the frequency values are carefully chosen to avoid aliasing effects, and provide coverage below, in and above the passband, with testing including assessment of filter roll-off characteristics — Calnex provide recommended input values and test masks directly in Paragonneo GUI
EEC Option 2	TDEV Wander Table 10, Figure 8.	Measure EEC output against TDEV Pass/Fail masks shown in G.8262 Section 10.2 Table 13, Figure 11.	it is suggested that the frequency values are carefully chosen to avoid aliasing effects, and provide coverage below, in and above the passband, with testing including assessment of filter roll-off characteristics – Calnex provide recommended input values and test masks directly in Paragonneo GUI

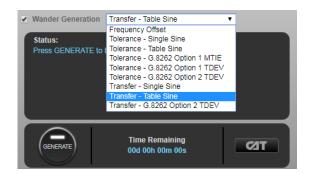
# **Measurement Setup**

- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3, including setting up ESMC with the following settings if using ESMC to monitor if the eEEC/EEC is switching clock references or going into holdover:

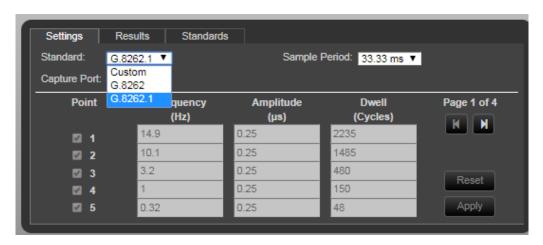
Clock Type	Network Option	SSM Code
eEEC	Option 1	QL-PRC
EEC Option 1	Option 1	QL-PRC
EEC Option 2	Option 2	QL-PRS

#### Measurement Process - eEEC

- 1. Tick the Wander Generation check box on the Paragon-neo GUI. Note, you may have to stop any running measurements and then tick the Wander Generation selection.
- 2. Select **Transfer Table Sine** from the drop-down menu.

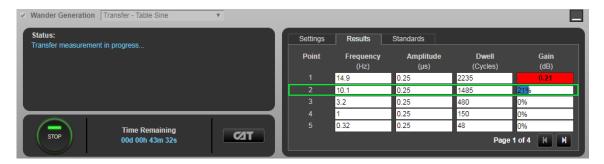


3. In Settings, select Standard:->G.8262.1 to populate the stimulus table (and allow appropriate limits to be applied to capture data):



button to start the test.

5. The Paragon-neo will show the estimated time remaining at the bottom of the screen and will indicate the progress as it runs through the test, with pass/fail indication for each test point once complete.

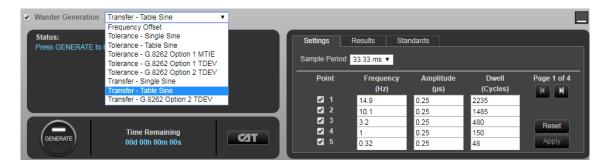


6. Launching CAT will provide a gain plot, and G.8262.1 limits can be applied, for visualization of DUT filter characteristics.

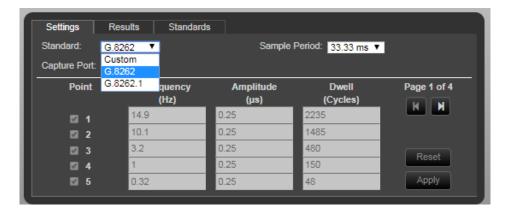


# Measurement Process - EEC Option 1

- Tick the Wander Generation check box on the Paragon-neo GUI. Note, you may have to stop any running measurements and then tick the Wander Generation selection.
- 2. Select **Transfer Table Sine** from the drop-down menu.



3. In Settings, select Standard:->G.8262 to populate the stimulus table (and allow appropriate limits to be applied to capture data):

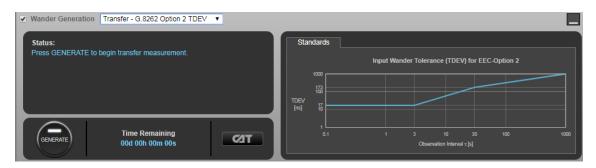


- Click the button to start the test.
- The Paragon-neo will show the estimated time remaining at the bottom of the screen and will indicate the progress as it runs through the test, with pass/fail indication for each test point once complete.
- 6. Launching CAT will provide a gain plot, and G.8262 EEC Opt 1 limits can be applied, for visualization of DUT filter characteristics.

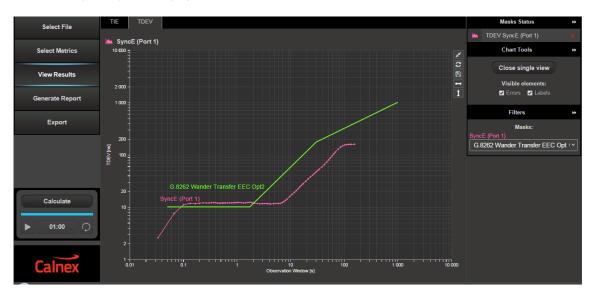


# **Measurement Process - EEC Option 2 TDEV**

Select Transfer - G.8262 Option 2 TDEV from the drop-down menu. This will display G.8262 TDEV Wander Tolerance mask for EEC-Option 2.



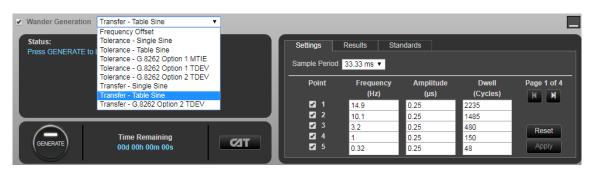
- button to start the test. Test duration is 3h 20m.
- 3. The amount of the time until completion of the test is shown at the bottom of the wander generation app.
- 4. At any time during the test, it is possible to view an updated output TDEV graph. To display the TDEV results, select to open CAT in a separate browser tab.
- 5. To display the TDEV graph in CAT click on the left-hand side of the graph, choose TDEV from the tabs at the top then press the play button in the Calculate box.



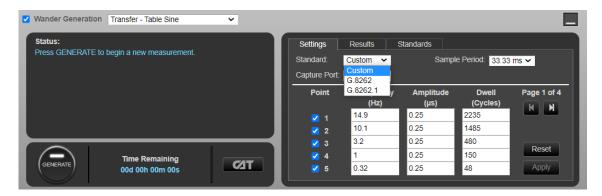
- 6. The TDEV results can be reviewed against the G.8262 masks by choosing the G.8262 Wander Transfer mask from the Metric Mask pull down menu under **Masks** at the right of the graph.
- 7. Pass/Fail indication against the masks is shown to the right under Mask Status Service with green highlight for a "Pass" and red highlight for a "Fail".

# Measurement Process - EEC Option 2 Using Tones

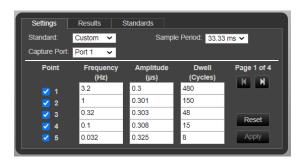
- 1. Tick the Wander Generation check box on the Paragon-neo GUI. Note, you may have to stop any running measurements and then tick the Wander Generation selection.
- 2. Select **Transfer Table Sine** from the drop-down menu.

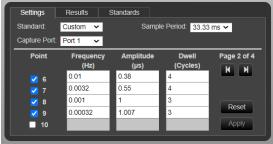


3. In **Settings**, select **Custom** to enable editing of the table of tones to be applied.

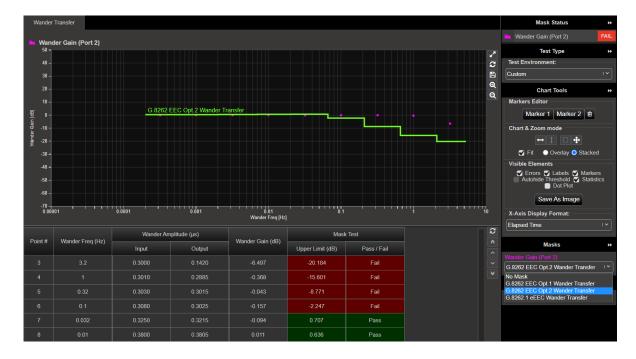


Enter the values below to configure the tones to be applied. Note that there are two pages.





- Click the button to start the test. Due to the low frequencies required, this
- The Paragon-neo will show the estimated time remaining at the bottom of the screen and will indicate the progress as it runs through the test, with pass/fail indication for each test point once complete.
- Launching CAT will provide a gain plot, and G.8262 EEC Opt 2 limits can be applied, for visualization of DUT filter characteristics. A G.8262 EEC Option 2 filter has no lower gain limit.



# Optional: Paragon-neo single frequency test

This capability can be used for fault finding issues that have occurred at specific frequencies.

1. Select **Transfer – Single Sine** from the drop-down menu.

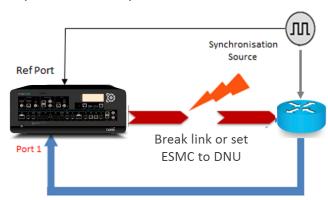


- 2. Enter the frequency and amplitude of the wander to be generated.
- 3. Click the button to start the test.
- 4. The Paragon-neo will show the estimated completion time at the bottom of the screen and will indicate the progress as it runs through the test, displaying the measured Gain (dB) value and also a Green (Pass)/Red (Fail) indication vs. 2dB on the last (Gain) column.



# 11. Phase Transient Response – G.8262.1/G.8262 Section 11

# **Short term phase transient response**



Measure Wander

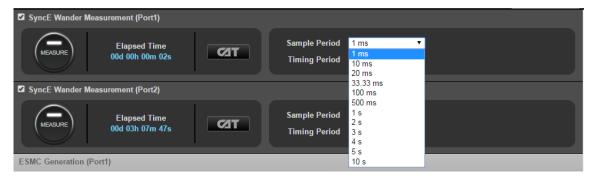
	Input Stimulus	Pass/Fail Criteria	Notes
eEEC	eEEC input reference is lost for up to 15 seconds and a second reference input signal, traceable to the same reference clock, is available simultaneously.	Maximum phase transient at the output due to reference switching to meet mask in G.8262.1 Figure 7.	To emulate the loss of the link either: Change ESMC QL=DNU (Option 1 Network) or Remove the cable between Port 2 and eEEC
EEC Option 1	EEC input reference is lost for up to 15 seconds and a second reference input signal, traceable to the same reference clock, is available simultaneously.	Maximum phase transient at the output due to reference switching to meet mask in G.8262 Figure 12.	To emulate the loss of the link either: Change ESMC QL=DNU (Option 1 Network) or Remove the cable between Port 2 and EEC
EEC Option 2	EEC input reference is lost for up to 15 seconds and a second reference input signal, traceable to the same reference clock, is available simultaneously.	EEC output should meet MTIE mask defined by Table 15, Figure 14 in Section 11.4.2 of G.8262.	To emulate the loss of the link either: Change ESMC QL=DUS (Option 2 Network) or Remove the cable between Port 2 and EEC

# **Measurement Setup**

- 1. Connect the eEEC/EEC to Paragon-neo as shown in the diagram at the beginning of this section.
- 2. Set up the Paragon-neo as described in Section 3, including setting up ESMC with the following settings if using ESMC to monitor if the eEEC/EEC is switching clock references or going into holdover:

Clock Type	Network Option	SSM Code
eEEC	Option 1	QL-PRC
EEC Option 1	Option 1	QL-PRC
EEC Option 2	Option 2	QL-PRS

3. For **SyncE Wander Measurement (Port 1),** open the **Sample Period** drop down menu and select a **1ms** sample period.



#### **Measurement Process**

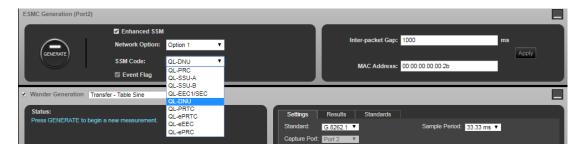
There are two methods for determining Phase Transient Response with the Paragon-neo:

- Use ESMC Generation (if supported by the DUT).
- Remove the link between Port 2 on the Paragon-neo and the eEEC/EEC input port.
- 1. Select the button on SyncE Wander Measurement (Port 1) to start the measurement.
- 2. Launch CAT to monitor results (see below).
- 3. Use one of the two methods described to create a disruption for a maximum of 15 seconds.
- 4. If using the Ethernet cable removal method, disconnect the cable between Port 2 and the eEEC/EEC, then reconnect after 15 seconds.
- 5. If using the ESMC method:
  - a) Refer to the ESMC Generation track for Port 2 as shown below.
  - b) Ensure SSM code is already set to e.g. QL-PRC (Option 1 Network) or QL\_PRS (Option 2 Network) and ensure





c) In the SSM Code drop down menu select **QL-DNU** (Option 1 Network) or **QL-DUS** (Option 2 Network).



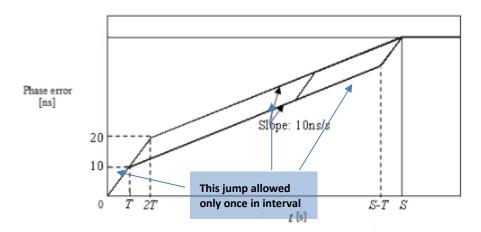
6. To stop the measurement, press the button on SyncE Wander Measurement (Port 1).

# **Measuring Results**

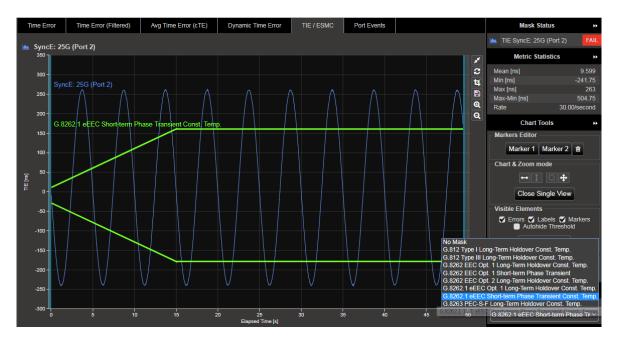
Note that the method of evaluating the capture for phase transient response is dependent on whether eEEC, EEC Option 1 or Option 2 is being evaluated.

#### **eEEC**

Monitor the output TIE graph in CAT over the duration (15s) of the test. While the subordinate clock is acquiring the new reference, the output phase transient should be within the limits of Figure 7 of G.8262.1 (provided below). Select the appropriate TIE mask from the drop-down menu on the right-hand side of the graph. Note that for eEEC devices, T=0, S=15.

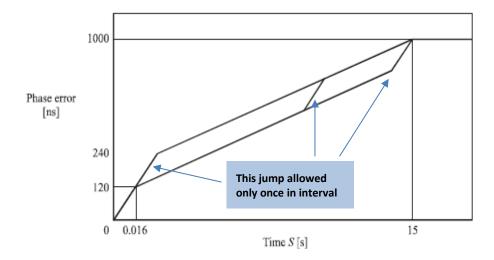


To ensure that the start of the mask is aligned with the start of the transient, left click and hold on the left side of the graph to use the drag function and move the data analysis range from the left of the measurement data to the visible start of the transient.



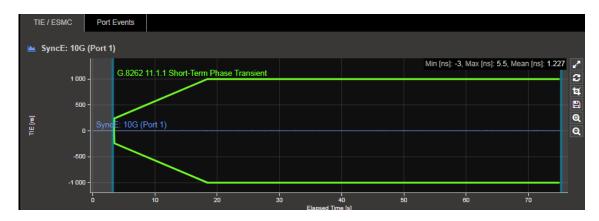
# **EEC Option 1**

To view the output TIE for EEC Option 1, monitor the output TIE graph in CAT over the duration (15s) of the test. While the subordinate clock is acquiring the new reference, the output phase transient should be within the limits of Figure 12 of G.8262 (provided below).



Select the appropriate TIE mask from the drop-down menu on the right-hand side of the graph.

To ensure that the start of the mask is aligned with the start of the transient, left click and hold on the left side of the graph to use the drag function and move the data analysis range from the left of the measurement data to the visible start of the transient.

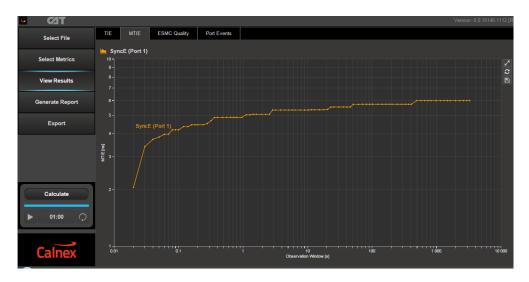


# **EEC Option 2**

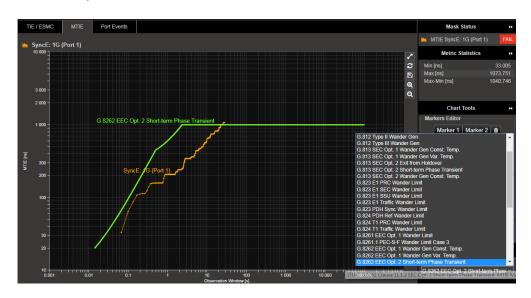
- 1. To view the output MTIE mask for EEC Option 2 **ONLY**, perform the following:
- 2. In CAT, choose **Select Metrics** and then tick the **MTIE** checkbox.



3. Select View Results then select the MTIE tab. Next, select the button on the left of the window. This will display the MTIE metrics graph.

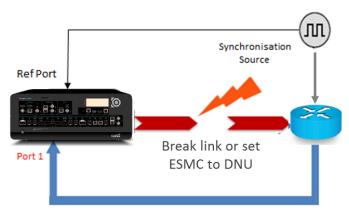


4. The MTIE analysis can be carried out against the G.8262 masks for Wander Transient which can be selected from the Metric Mask pull down selection at the bottom of the window.



5. Pass/Fail indication is shown to the right under Mask Status Service with green highlight for "Pass" and red for "Fail".

# 12. Long-term phase transient response (holdover)

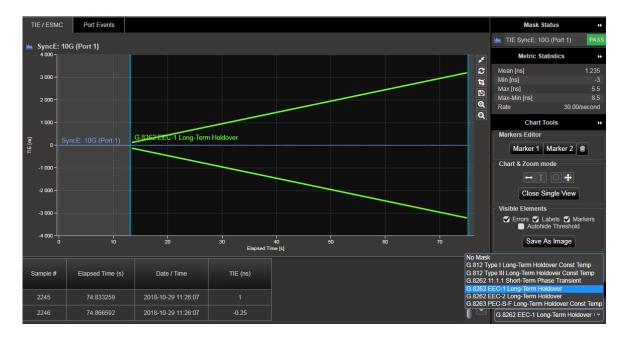


Measure Wander

	Input Stimulus	Pass/Fail Criteria	Notes
eEEC	eEEC input reference is permanently lost or declared DNU.	Maximum phase transient and excursion at the output due to reference switching to meet mask in G.8262.1 Figure 8.	To emulate the loss of the link either: Change ESMC QL=DNU (Option 1 Network) or Remove the cable between Port 2 and eEEC Measure for 10,000 seconds (approx. 3hrs)
EEC Option 1	EEC input reference is permanently lost or declared DNU.	Maximum phase transient and excursion at the output due to reference switching to meet mask in G.8262 Figure 13.	To emulate the loss of the link either: Change ESMC QL=DNU (Option 1 Network) or Remove the cable between Port 2 and EEC Measure for 10,000 seconds (approx. 3hrs)
EEC Option 2	EEC input reference is permanently lost or declared DNU.	Maximum phase transient and excursion at the output due to reference switching to meet mask in G.8262 11.2.2 and Table 14, including 1st and 2nd derivatives of phase vs time.	To emulate the loss of the link either: Change ESMC QL=DNU (Option 2 Network) or Remove the cable between Port 2 and EEC Measure for 10,000 seconds (approx. 3hrs)

#### **Measurement Setup and Process**

- Set the ESMC being generated on Port 2 of the Paragon-neo to e.g. QL-PRC (Option 1 Network) or QL-PRS (Option 2 Network). This will cause the DUT to lock to this signal and hence to the Synchronization Source.
- 2. After allowing the DUT to settle [leave for at least 900s (15 minutes)] measure the wander on Port 1. The resulting graph should be flat and the Offset measurement at the bottom of the Wander TIE graph should indicate 0.000 ppm. The ESMC received from the DUT on Port 1 should match the input QL (e.g. QL-PRC or QL-PRS)
- 3. Restart the wander measurement and then set the ESMC on Port 2 to DNU (Option 1 Network, Do Not Use) or QL-DUS (Option 2 Network, Don't Use for Synchronization). This should cause the DUT to search for an alternative master clock signal to lock to. As there are no other external signals the DUT will use its internal clock. The ESMC messages on Port 1 should reflect this change with the appropriate Quality Level e.g. EEC1.
- 4. The **TIE** graph should show the SyncE signal from the DUT start to drift off. Leave the capture running for a minimum of 10,000 seconds (approx. 3 hours) then stop the measurement.
- 5. Monitor the output TIE graph via CAT after completion (10 000s) of the test. The output TIE should be within the limits shown above for the chosen device type. Select the appropriate TIE mask from the drop-down menu on the right-hand side of the graph. To ensure that the start of the mask is aligned with the start of the transient, left click and hold on the left side of the graph to use the drag function and move the data analysis range from the left of the measurement data to the visible start of the transient.



6. Pass/Fail indication against the masks is shown to the right under Mask Status Service with green highlight for a "Pass" and red highlight for a "Fail"



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